

Outline

- motivation
 - the Sun's electromagnetic spectrum
 - spectroscopic methods
 - observational examples
- instrumental aspects
 - optical design
 - detectors
 - others
- highlights and outlook

EUV Spectroscopy





Spectroscopic methods

- line identification / selection
- line shifts / Doppler flows
- line widths / line shape
- plasma diagnostics / line ratios
- raster scans
- drift scans
- abundance measurements / FIP effect
- radiance / irradiance
- atomic physics EUV Spectroscopy















Line shape

- emission profile $\Psi(\lambda)$ $\Psi(\lambda) = \Psi(\lambda)_{nat} * \Psi(\lambda)_{coll} * \Psi(\lambda)_{th} * \Psi(\lambda)_{NT}$
- Optically thin emission lines are Gaussians
- $\Delta \lambda_{\rm D} = \lambda_0 / c \ (2kT/m + \xi^2)^{1/2}$ $\xi \text{ non-thermal velocity (turbulence)}$







Performance characteristic

| Solar Ultraviolet Measu | rement of Emitted | Radiation | |
|-------------------------|-------------------|--------------|---------------|
| | CDS | SUMER | EIS |
| wavelegth range, Å | 308-381 (NI) | 790-1608 (1) | 180 - 204 (A) |
| | 513-633 | 465-804 (2) | 240 - 290 (B) |
| | 151-221 (GI) | | |
| | 256-338 | | |
| | 393-493 | | |
| | 656-785 | | |
| spatial resolution / " | 4 - 8 | 1.2 | 1 |
| spectral " / km/s | 10 | 2 | 2-3 |
| temporal " / s | 10 | 10 | 1 |
| | | | |
| | | | |
| | | | |

Instrumental aspects

- Spectroscope:
 - telescope
 - slit
 - dispersive element
 - 2D detector
- infrastructure
 - to bring the instrument into space
 - to bring the data back to Earth

EUV Spectroscopy





Telescope slit

- slit width limits photon input
- slit width limits spectral resolution
- slit: loss of >99% of photons
 - slitless spectroscopes (strong lines, filters)
 - slot spectroscopes (wide slit)
 - raster scans
 - drift scans (low temporal resolution)

EUV Spectroscopy

Telescope collimator

- Makes parallel light (classical design)
- defines magnification (pixel adjustment)
- folds the light beam (compactness)

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Spectroscope grating

- Bragg crystal systems
- holographic gratings
- ruled gratings
- variable line space technique (TVLS)
 - future 2 reflection designs

Instrument detector(s)

- Films
- CCDs
 - back-illuminated CCDs
 - intensified CCDs
- MCP detectors
 - multianode systems (MAMA)
 - time delay systems (XDL)
- APS sensors
- BOLD detectors EUV Spectroscopy

| 16 bit pixels 1 k × 1k 10 s | dynamical range small and numerous good time resolution | |
|---|---|-------------|
| | | |
| Example SUMER: <u>1</u> | <u>6 bit/px_x_400 000 bit</u> 10 s | ≈500 kbit/s |
| Example SUMER: <u>1</u> Data selection | <u>6 bit/px × 400 000 bit</u> 10 s windows, binning | ≈500 kbit/s |
| Example SUMER: <u>1</u> Data selection Data compression | <u>6 bit/px × 400 000 bit</u> 10 s windows, binning sqrt, JPEG, MPEG | ≈500 kbit/s |













